

<b>Notice of References Cited</b>	Application/Control No. 10/790,208	Applicant(s)/Patent Under Reexamination SHIMIZU, KOICHI	
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	V	Spinu et al., "Micromagnetic Calculation of the Transverse Susceptibility of Patterned Media", IEEE, 2003.			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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